

# 2SJ504

Silicon P Channel MOS FET  
High Speed Power Switching

# HITACHI

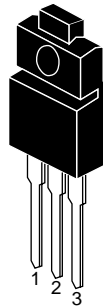
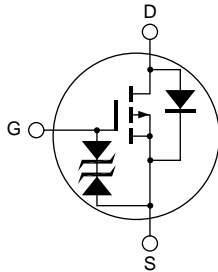
ADE-208-546  
Target specification 1st. Edition

## Features

- Low on-resistance  
 $R_{DS(on)} = 0.042\Omega$  typ.
- Low drive current.
- 4V gate drive devices.
- High speed switching.

## Outline

TO-220FM



1. Gate
2. Drain
3. Source

**Absolute Maximum Ratings** ( $T_a = 25^\circ\text{C}$ )

<b>Item</b>	<b>Symbol</b>	<b>Ratings</b>	<b>Unit</b>
Drain to source voltage	$V_{DSS}$	-60	V
Gate to source voltage	$V_{GSS}$	$\pm 20$	V
Drain current	$I_D$	-20	A
Drain peak current	$I_{D(pulse)}^{*1}$	-80	A
Body to drain diode reverse drain current	$I_{DR}$	-20	A
Avalanche current	$I_{AP}^{*3}$	-20	A
Avalanche energy	$E_{AR}^{*3}$	34	mJ
Channel dissipation	$P_{ch}^{*2}$	30	W
Channel temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

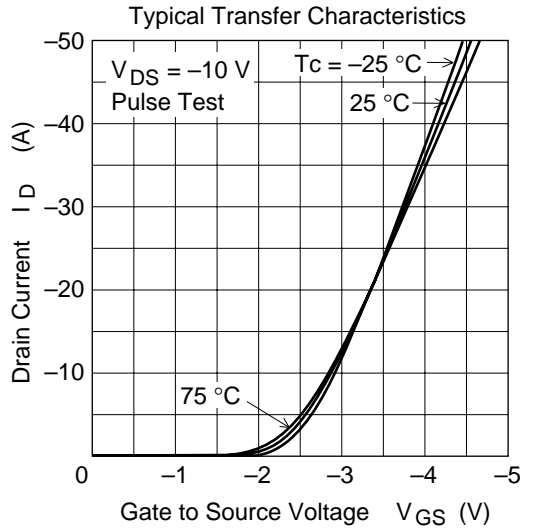
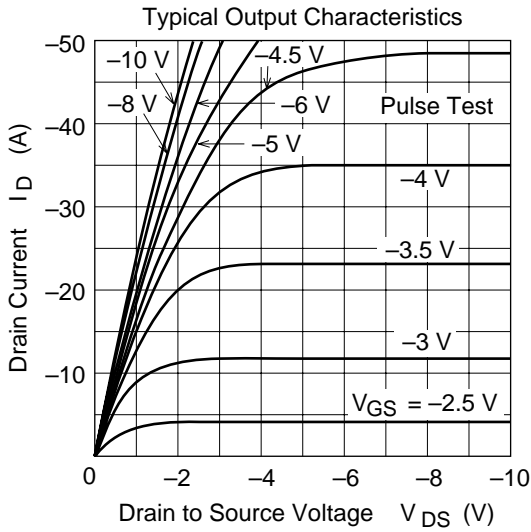
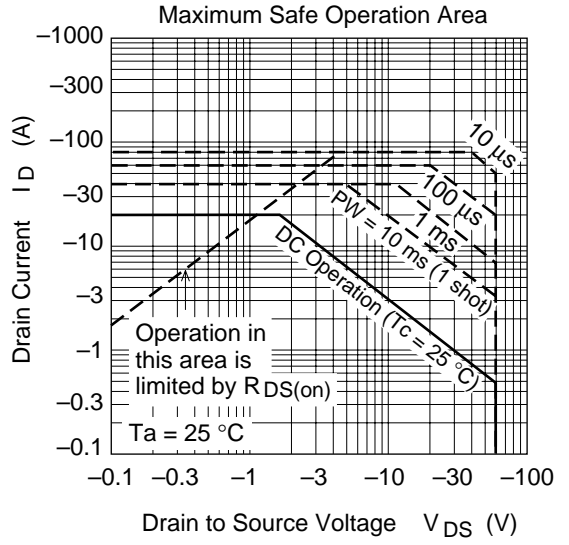
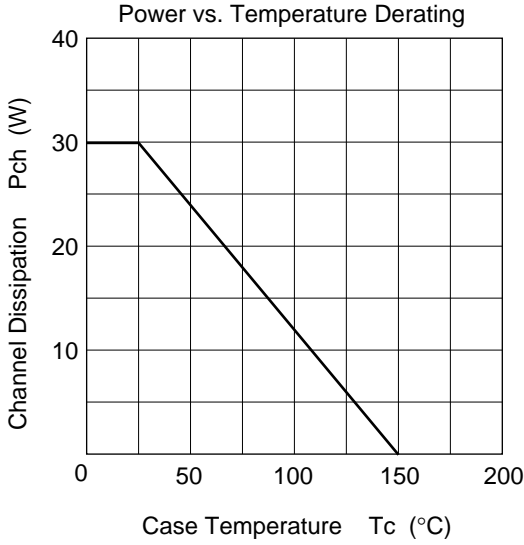
- Notes: 1.  $PW \leq 10\mu\text{s}$ , duty cycle  $\leq 1\%$   
2. Value at  $T_c = 25^\circ\text{C}$   
3. Value at  $T_a = 25^\circ\text{C}$ ,  $R_g \geq 50\ \Omega$ ,  $L=100\mu\text{H}$

## Electrical Characteristics (Ta = 25°C)

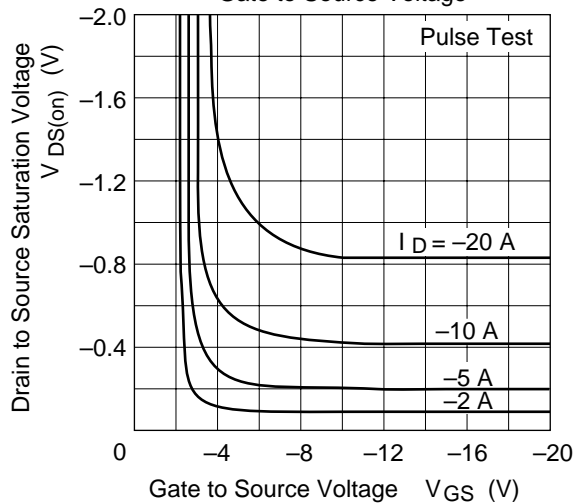
Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	-60	—	—	V	$I_D = -10\text{mA}$ , $V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	$\pm 20$	—	—	V	$I_G = \pm 100\mu\text{A}$ , $V_{DS} = 0$
Zero gate voltage drain current	$I_{DSS}$	—	—	-10	$\mu\text{A}$	$V_{DS} = -60\text{V}$ , $V_{GS} = 0$
Gate to source leak current	$I_{GSS}$	—	—	$\pm 10$	$\mu\text{A}$	$V_{GS} = \pm 16\text{V}$ , $V_{DS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	-1.0	—	-2.0	V	$I_D = -1\text{mA}$ , $V_{DS} = -10\text{V}$
Static drain to source on state resistance	$R_{DS(on)}$	—	0.042	0.055	$\Omega$	$I_D = -10\text{A}$ , $V_{GS} = -10\text{V}^{*1}$
	$R_{DS(on)}$	—	0.065	0.095	$\Omega$	$I_D = -10\text{A}$ , $V_{GS} = -4\text{V}^{*1}$
Forward transfer admittance	$ y_{fs} $	10	16	—	S	$I_D = 10\text{A}$ , $V_{DS} = 10\text{V}^{*1}$
Input capacitance	$C_{iss}$	—	1750	—	pF	$V_{DS} = -10\text{V}$
Output capacitance	$C_{oss}$	—	800	—	pF	$V_{GS} = 0$
Reverse transfer capacitance	$C_{rss}$	—	180	—	pF	$f = 1\text{MHz}$
Turn-on delay time	$t_{d(on)}$	—	16	—	ns	$V_{GS} = -10\text{V}$ , $I_D = -10\text{A}$
Rise time	$t_r$	—	100	—	ns	$R_L = 3\Omega$
Turn-off delay time	$t_{d(off)}$	—	230	—	ns	
Fall time	$t_f$	—	140	—	ns	
Body to drain diode forward voltage	$V_{DF}$	—	-1.0	—	V	$I_F = -20\text{A}$ , $V_{GS} = 0$
Body to drain diode reverse recovery time	$t_{rr}$	—	100	—	ns	$I_F = -20\text{A}$ , $V_{GS} = 0$ $diF/dt = 50\text{A}/\mu\text{s}$

Note: 1. Pulse test

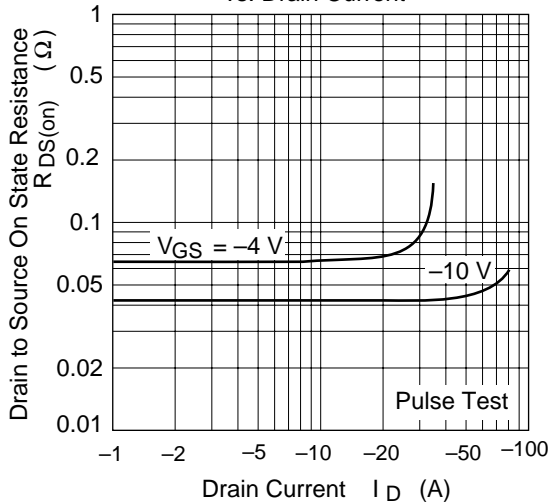
Main Characteristics



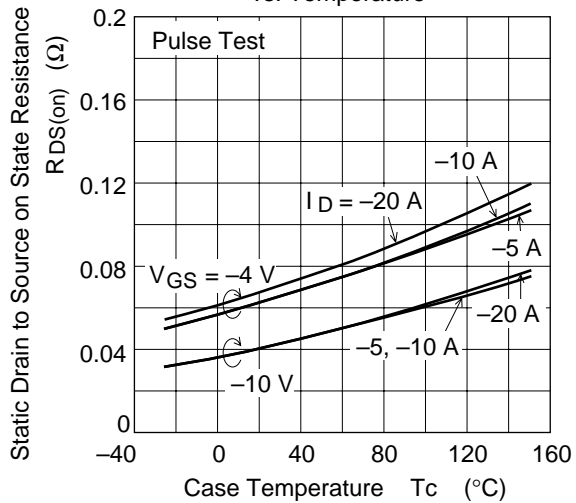
Drain to Source Saturation Voltage vs. Gate to Source Voltage



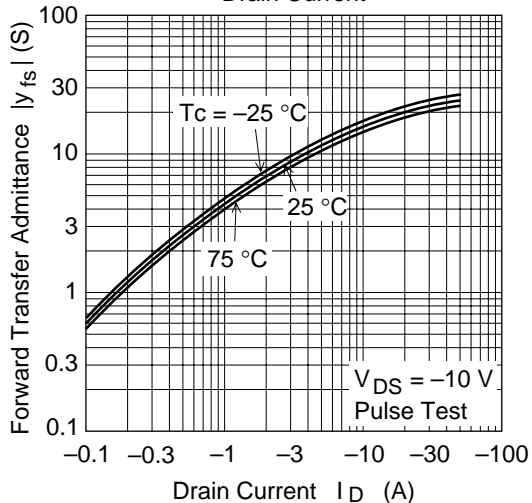
Static Drain to Source on State Resistance vs. Drain Current



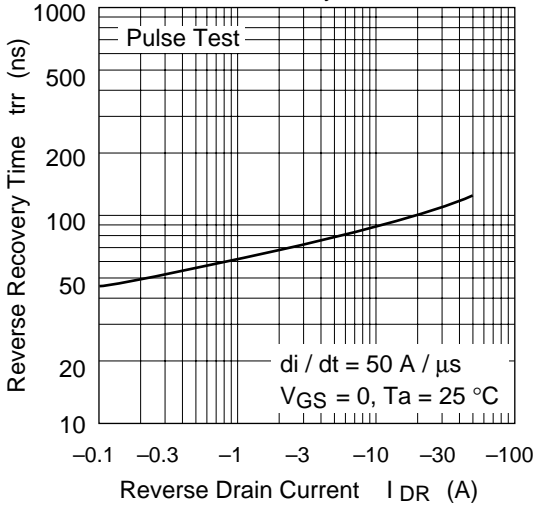
Static Drain to Source on State Resistance vs. Temperature



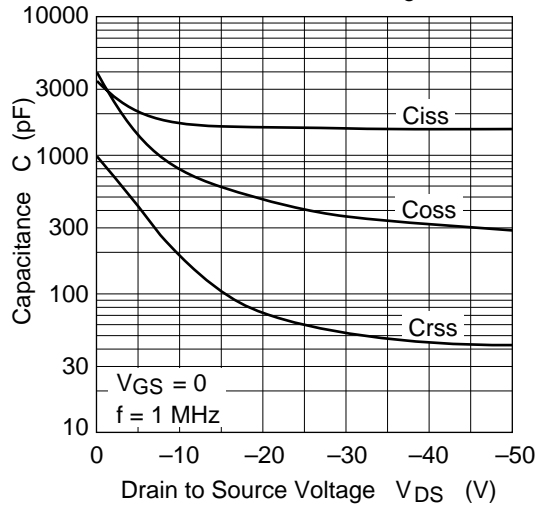
Forward Transfer Admittance vs. Drain Current



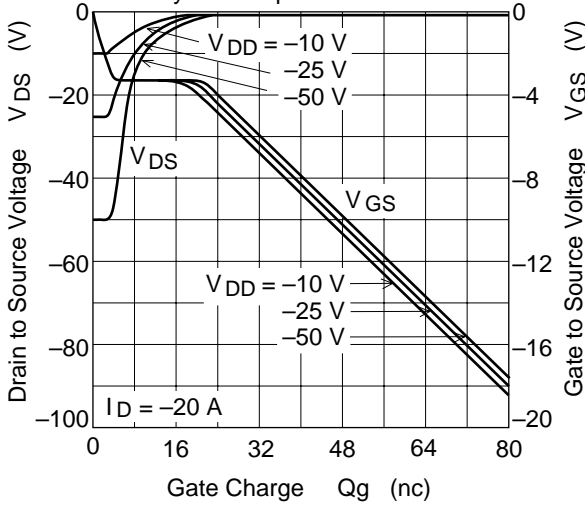
Body to Drain Diode Reverse Recovery Time



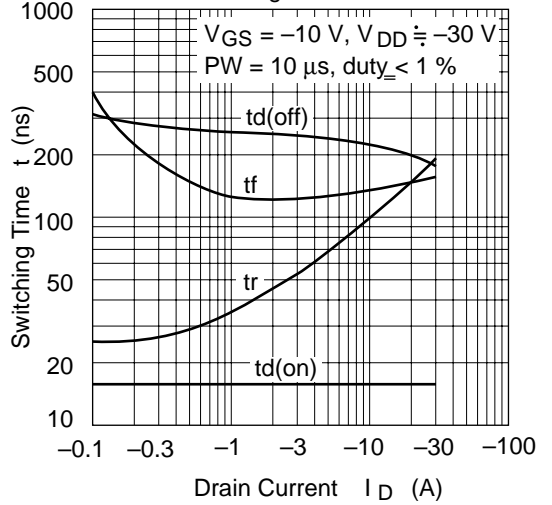
Typical Capacitance vs. Drain to Source Voltage

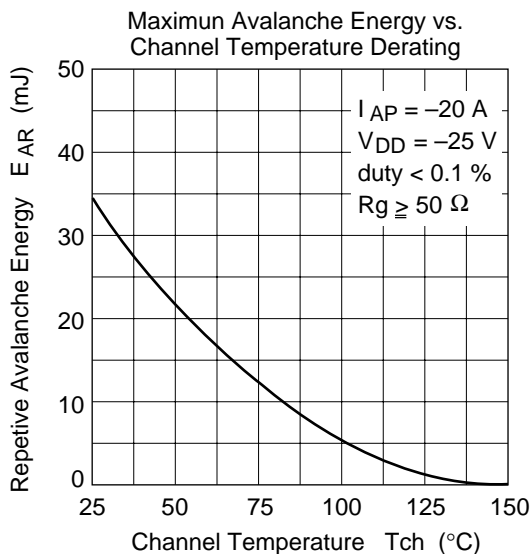
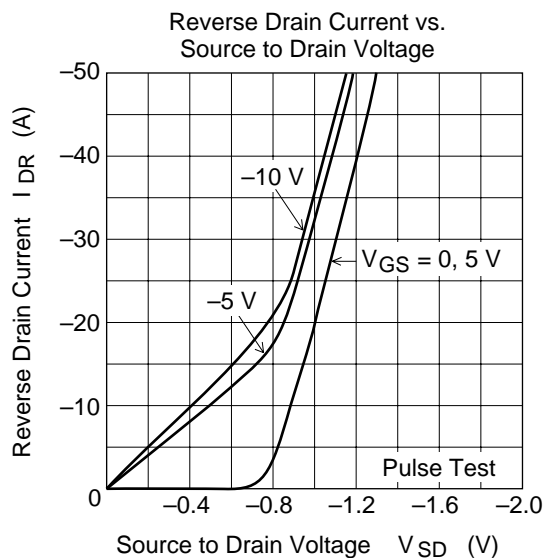


Dynamic Input Characteristics

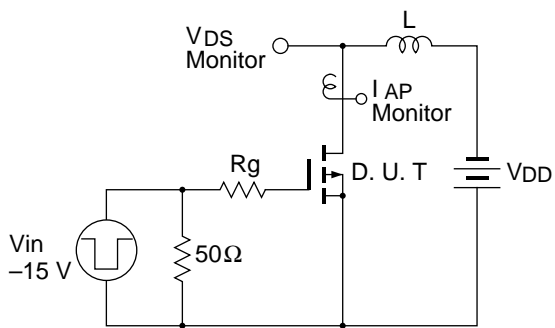


Switching Characteristics

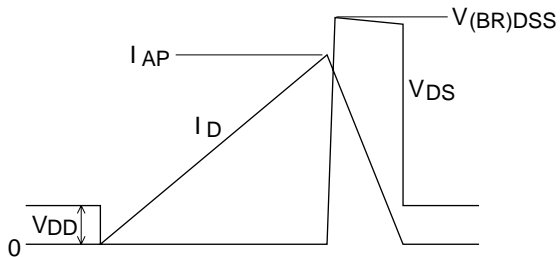




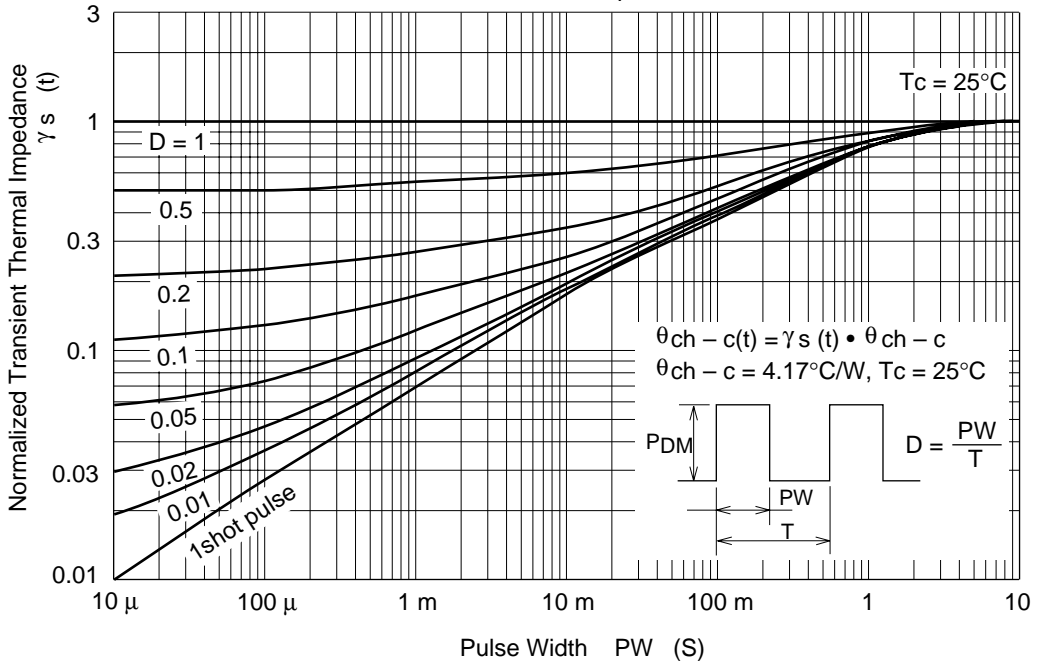
Avalanche Test Circuit and Waveform



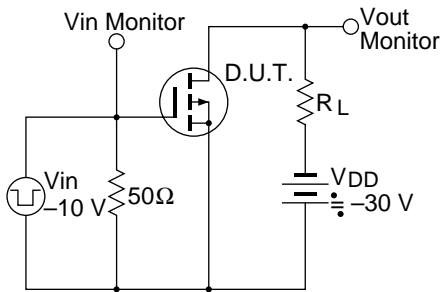
$$E_{AR} = \frac{1}{2} \cdot L \cdot I_{AP}^2 \cdot \frac{V_{DSS}}{V_{DSS} - V_{DD}}$$



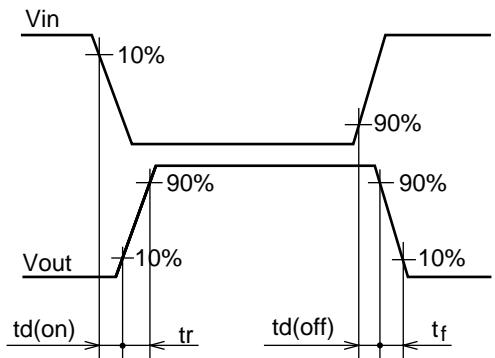
Normalized Transient Thermal Impedance vs. Pulse Width



Switching Time Test Circuit



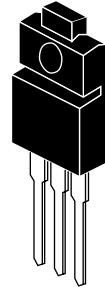
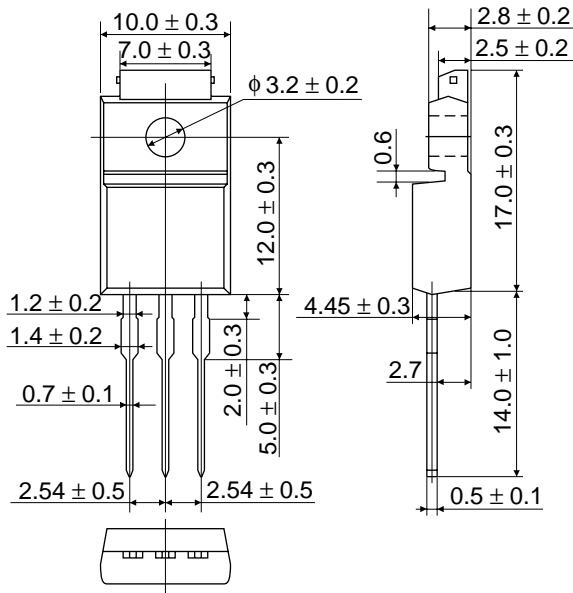
Waveforms





## Package Dimensions

Unit: mm



Hitachi Code	TO-220FM
EIAJ	SC-67
JEDEC	—

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